

STL9524

In the Abstract:

Please amend the abstract as follows:

COMPREHENSIVE APPLICATION POWER TESTER**Abstract of the Disclosure**

a1 An electronic device power testing method is provided in which applying a nominal voltage to an electronic component, introducing a voltage disruption to the nominal voltage, and repeating the voltage disruption for a specified number of instances is done. The present invention also can be implemented as an electronic device power tester.
